查询"2SK386β"為麻腐 Field Effect Transistor Silicon N-Channel MOS Type (π-MOSVI)

2SK3863

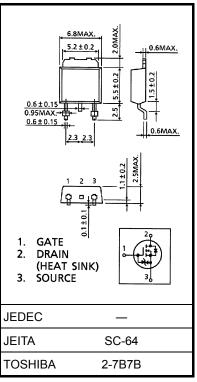
Switching Regulator Applications

Unit: mm

- Low drain-source ON resistance: RDS (ON) = 1.35Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 2.8S$ (typ.)
- Low leakage current: $I_{DSS} = 100 \, \mu \, A \, (V_{DS} = 500 \, V)$
- Enhancement model: $V_{th} = 2.0 \sim 4.0 \text{ V} \text{ (V}_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	500	V	
Gate-source voltage		V _{GSS}	±30	V	
Drain current	DC (Note 1)	ID	5	А	
	Pulse (t = 1 ms) (Note 1)	I _{DP}	20		
Drain power dissipation (Tc = 25°C)		P _D	40	W	
Single pulse avalanche energy (Note 2)		E _{AS}	180	mJ	
Avalanche current		I _{AR}	5	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	4	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	



Weight: 0.36 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

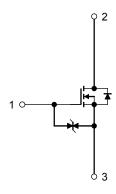
Characteristic	Symbol	Max	Unit	
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W	

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 12.2 mH, $I_{AR} = 5 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



Energy istics (Ta = 25°C)

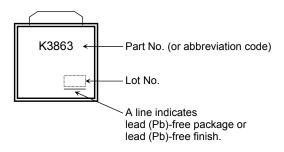
Chai	racteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rent	I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Gate-source brea	akdown voltage	V (BR) GSS	$I_D = \pm 10 \ \mu A, \ V_{GS} = 0 \ V$	±30	_	_	V
Drain cutoff curre	ent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μА
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	500	_	_	V
Gate threshold ve	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 2.5 A	_	1.35	1.50	Ω
Forward transfer	admittance	Yfs	V _{DS} = 10 V, I _D = 2.5 A	1.4	2.8	_	S
Input capacitance		C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	550	_	pF
Reverse transfer capacitance		C _{rss}			7		
Output capacitance		Coss		_	70	_	
Switching time	Rise time	t _r	$\begin{array}{c c} 10 \text{ V} & \text{I}_D = 2.5 \text{ A} & \text{V}_{\text{OUT}} \\ \hline \\ 15 \Omega & \text{ RL} = \\ 15 \Omega & \text{ 90 } \Omega \\ \hline \\ \text{V}_{DD} \simeq 225 \text{ V} \\ \\ \text{Duty} \leq 1\%, \ t_{\text{W}} = 10 \ \mu\text{s} \end{array}$	_	10	_	
	Turn-on time	t _{on}		_	20	_	
	Fall time	t _f		_	10	_	ns
	Turn-off time	t _{off}		_	50	_	
Total gate charge		Qg		_	16	_	
Gate-source charge		Q _{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$	_	10	_	nC
Gate-drain charge		Q _{gd}			6	_	

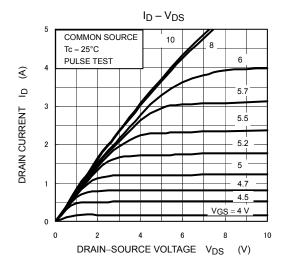
Source-Drain Ratings and Characteristics (Ta = 25°C)

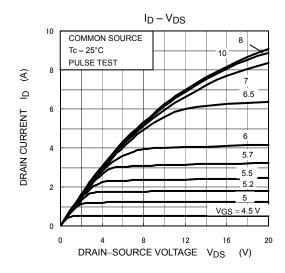
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	5	А
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	20	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 5 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 5 \text{ A}, V_{GS} = 0 \text{ V},$	_	1400	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} /dt = 100 A/μs	_	9	_	μС

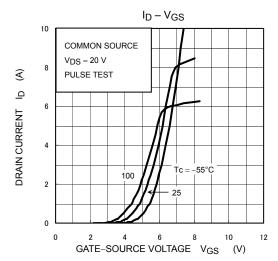
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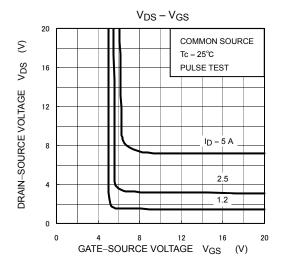
Marking

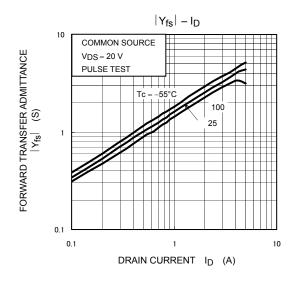


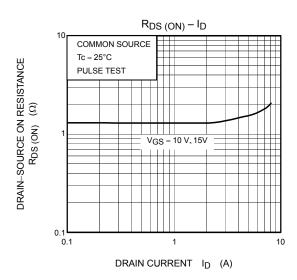


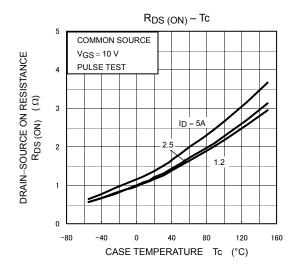


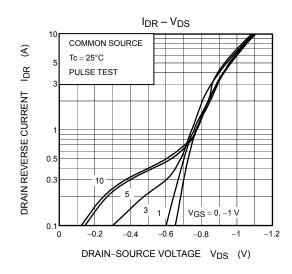


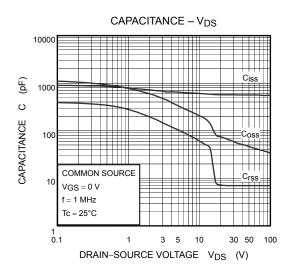


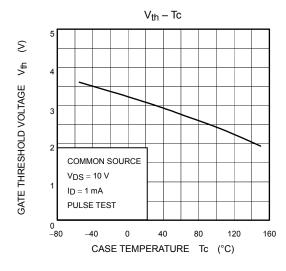


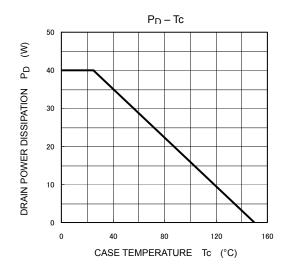


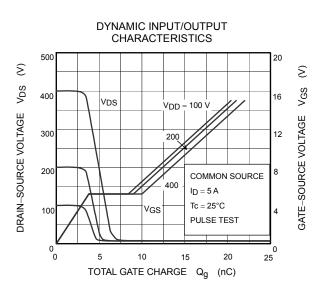


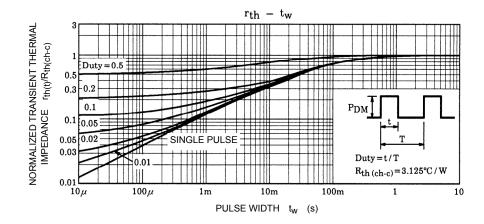


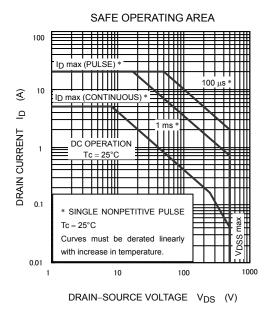


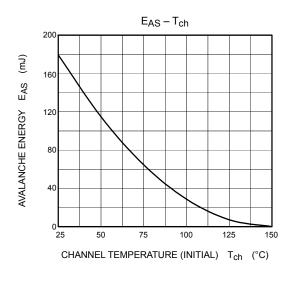


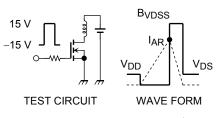












$$R_G = 25 \Omega$$

 $V_{DD} = 90 \text{ V, L} = 12.2 \text{ mH}$ $E_{AS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left(\frac{BVDSS}{BVDSS} - V_{DD}\right)$

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